

2 inch AlN on Sapphire Templates



产品型号 Item	AIN-T-C-C50
尺寸 Dimensions	$\Phi 50.8 \pm 0.1$ mm
厚度 Thickness	4 ± 1.5 μ m
晶体取向 Orientation	C-plane (0001)
导电类型 Conduction Type	Semi-Insulating
晶体质量 Crystalline quality	XRD FWHM of (0002) < 350 arcsec. XRD FWHM of (10-12) < 450 arcsec
表面粗糙度 Surface Roughness	Ra < 5 nm (10 x 10 μ m ²)
衬底结构 Substrate Structure	AlN on sapphire(SSP)
有效面积 Usable Surface	Exclusion zone <2mm
包装 Package	Packaged in a class 100 clean room environment, in cassettes of 25pcs or single wafer containers, under a nitrogen atmosphere.

